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In the Claims:

Please cancel claims 1-11, 14-16 and 50-53. Further please amend claims 12 and 13 as indicated in the list of pending claims as follows:

1-11. (Cancelled)

12. (Currently Amended) The A probe card assembly of claim 11 for testing a device comprising:

a substrate with probe contacts on a first surface;

a probe card to electrically connect said probe contacts to a test system;

an electrical connection means to connect the probe contacts to the probe card; and

support means positioned against a second surface of the substrate substantially opposite

said probe contacts without electrically connecting to the probe contacts, the support means

transmitting probe forces introduced when the probe contacts are urged against corresponding

contacts on the device being tested; and

a frame provided around a peripheral edge of the substrate, the frame including a horizontal extension extending over the surface of the substrate, wherein the probe forces are

transmitted by the support means to the frame, wherein the horizontal extension of the frame

includes a load support member extending vertically from a surface of the horizontal extension to

engage the first surface of the substrate in an area separated from the peripheral edge of the

substrate.

13. (Currently Amended) The A probe card assembly of claim 11, further for testing a device comprising:

a substrate with probe contacts on a first surface;

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Thanks!

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